FORM PTO-1449

EXAMINER INITIAL

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US 6,178,823

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

01/2001

Sykes

FILING DATE

March 1, 2002

(USE SEVERAL SHEETS IF NECESSARY)

ATTY. DOCKET NO.	APPLICATION NO.
MEISS89.001AUS	10/090,083
APPLICANT FARASSAT, Farhad	

GROUP

1725

	, <u>, , , , , , , , , , , , , , , , , , </u>	U.S. PATENT DOCUMENTS			
DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
US 3,572,108	03/1971	McShane et al.			
US 4,445,378	05/1984	Zuckerwar			
US 4,453,414	06/1984	Ronemus et al.			
US 4,619,397	10/1986	Urban			
US 4,895,028	01/1990	Mayer			
US 4,907,458	03/1990	Biggs et al.			
US 4,984,730	01/1991	Göbel et al.			
US 5,213,249	05/1993	Long et al.			
US 5,275,058	01/1994	Pham et al.			
US 5,314,105	05/1994	Farassat			
US 6,178,823	01/2001	Sykes			:
US 5,889,210	03/1999	Inoue			

				FOREIGN PATENT DOCUMENTS				
EXAMINER DOCUMENT NUMBER		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
INITIAL		•					YES	NO
1 16	14	EP 0263542	08/1987	Europe			n/a	
1	15	JP 2-90038	03/1990	Japan			abstract only	
	16	GB 2271305	04/1994	Great Britain			n/a	
	17	DE 4447073	07/1996	Germany			abstract only	
	18	EP 0772036	05/1997	Europe			n/a	
1	19	JP 2001–118887	04/2001	Japan			abstract only	

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EXAMINER	R			DATE CONSIDERED	5/12/05	
	-		ICO 00 NOT 0171710N	IS IN CONFORMANCE WIT	AL MOED CON ODAW LINE THEO	LICH CITATION IF NOT

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPÉP 609; DRAW LINE THROUGH CITATION IF NO IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MEISS69.001AUS	APPLICATION NO. 10/090,083	
	MATION DISCLOSURE STATEMENT Y APPLICANT	APPLICANT FARASSAT, Farhad		
(USE SEVERA	L SHEETS IF NECESSARY)	FILING DATE March 1, 2002	GROUP 1725	

EXAMINER INITIAL				
1100		"Bond testing enters mainstream PCB assembly" by Paul WALTER, Microelectronics Journal, Mackinstosh Publications LTD. Luton, GB, Bd. 27, Nr. 1, (February 1996)		
$\sim 1/$	21	"An Improved Wire Bond Pull Test" by Shankara PRASAD and Ali SABOUI, Solid State Technology, Cowan Publ. Corp., Washington, US, Bd. 34, Nr. 6, (June 1991)		
1/16	22	"Wire Bond Pull Testing Understanding the Geometric Resolution of Forces" by Gil PERLBERG and Cyndy ENMAN, Advanced Packaging, IHS Publishing Group, US, Bd. 3, Nr. 1, (1994)		

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EXAMINER & DATE CONSIDERED 5/12/05